

















# Bakerenkov Aleksandr S.

## Course Schedule









### MONDAY

12:45 — 14:20	<input checked="" type="checkbox"/> <b>SEM</b> Design of Integrated Circuits and Systems-on-Chip (SOC) <b>(2024-10-28 — 2024-12-09)</b>  M23-423  D-407
14:30 — 16:05	<input checked="" type="checkbox"/> <b>LAB</b> Design of Integrated Circuits and Systems-on-Chip (SOC)  M23-423  D-407
	<input checked="" type="checkbox"/> <b>SEM</b> Design of Integrated Circuits and Systems-on-Chip (SOC)  M23-423  D-407

### WEDNESDAY

12:45 — 14:20	<input checked="" type="checkbox"/> <b>SEM</b> Design of Integrated Circuits and Systems-on-Chip (SOC)  M24-403  D-407
14:30 — 16:05	<input checked="" type="checkbox"/> <b>LAB</b> Design of Integrated Circuits and Systems-on-Chip (SOC) <b>(2024-10-02 — 2024-12-18)</b>  M24-403  D-407
17:55 — 19:30	<input checked="" type="checkbox"/> <b>LEC</b> Reliability and radiation resistance of integrated circuits  M24-423  B-221
	<input checked="" type="checkbox"/> <b>SEM</b> Reliability and radiation resistance of integrated circuits  M24-423  B-218
19:35 — 21:10	<input checked="" type="checkbox"/> <b>LAB</b> Reliability and radiation resistance of integrated circuits  M24-423  B-218

### THURSDAY

14:30 — 17:50	<input checked="" type="checkbox"/> <b>LEC</b> Design of Integrated Circuits and Systems-on-Chip (SOC) <b>(2024-09-05 — 2024-09-19)</b>  M23-483  D-407
	<input checked="" type="checkbox"/> <b>SEM</b> Design of Integrated Circuits and Systems-on-Chip (SOC) <b>(2024-10-03 — 2024-12-12)</b>  M23-483  D-407
17:55 — 18:40	<input checked="" type="checkbox"/> <b>LEC</b> Reliability and Radiation Resistance of Microelectronic Devices and Systems  M23-403  K-407
18:45 — 20:20	<input checked="" type="checkbox"/> <b>SEM</b> Reliability and Radiation Resistance of Microelectronic Devices and Systems  M23-403  K-407